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3501-1007

PATENTS

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

#5

In re application of

Jussi TENHUNEN et al.

Confirmation No. Unassigned

Serial No. 10/089,161

Group Unassigned

Filed March 27, 2002

Examiner Unassisgned

SPECTROMETER AND METHOD FOR MEASURING OPTICAL SPECTRUM

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents

Washington, D.C. 20231

Sir:

In compliance with Rules 1.97 and 1.98, and in fulfillment of the duty of disclosure under Rule 1.56, the following documents, copies of which are attached to this statement, are made of record on the enclosed sheet.

A concise explanation of the relevance of the items listed on page 1 of the attached PTO Form 1449 is that we are advised by our client that these references were discovered during any searches they or their client had made, or that they were considered in the preparation of the application:

In addition, the remaining documents, copies of which are attached to this statement, are also made of record on the enclosed sheet.

A concise explanation of the relevance of these latter items listed on page 2 of the attached PTO Form 1449 is that we are advised by our client that these references were cited in the International Search Report in the corresponding

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International application Serial No. PCT/FI00/00824, filed September 27, 2000, and by the Finnish Patent Office in the corresponding Finnish Application Serial No. 19992092, filed September 29, 1999. Copies of the International Search Report and Finnish Official Action in which they were cited are attached hereto.

Respectfully submitted,

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By



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June 14, 2002

FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. 3501-1007	SEIAL NO. 10/089,161
INFORMATION DISCLOSURE STATEMENT BY APPLICANT <small>(Use several sheets if necessary)</small>		APPLICANT Jussi TENHUNEN et al.	
37 CFR 1.98(b)	JUN 14 2002 PTO-1449		FILING DATE00 March 27, 2002
GROUP Unassigned			

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	PATENT NUMBER	ISSUE DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
AA	5,504,575	04/96	Stafford			
AB	4,615,619	10/86	Fateley			
AC	3,859,515	01/75	Radcliffe			
AD						

FOREIGN PATENT OR PUBLISHED FOREIGN PATENT APPLICATION

	DOCUMENT NO.	PUBL. DATE	COUNTRY OR PATENT OFFICE	CLASS	SUB CLASS	TRANSLATION YES NO
AI						
AJ						

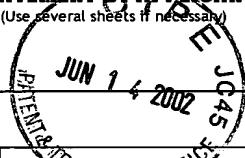
OTHER DOCUMENTS (including Author, Title, Date, Relevant Pages, Place of Publication)

AT	James D. Batchelor et al., "Development of a Digital Micromirror Spectrometer for Analytical Atomic Spectrometry," <u>Analytical Chemistry</u> , V. 70, 1998, pp. 4907-4914.
AU	P. Krippner et al., "Microspectrometer for the Infrared Range," <u>SPIE</u> , V. 2783, 1996, pp. 277-282.
AV	P. Rai-Choudhury, ed., <u>Handbook of Microlithography, Micromachining, and Microfabrication</u> , Vol. 2: Micromachining and Microfabrication, 1997, IEE, pp. 236-376.
AX	Martin Harwit et al., <u>Hadamard Transform Optics</u> , Academic Press, 1979, pp. v-ix.
AY	J. A. Decker, Jr., "Experimental Realization of the Multiplex Advantage with a Hadamard-Transform Spectrometer," <u>Applied Optics</u> , V. 10, 1971, pp. 510-514.

EXAMINER**DATE CONSIDERED**

EXAMINER: Initial citation considered. Draw line through citation if not in conformance and not considered.
Include copy of this form with next communication to applicant.

FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. 3501-1007	SERIAL NO. 10/089, 161
INFORMATION DISCLOSURE STATEMENT BY APPLICANT <small>(Use several sheets if necessary)</small>		APPLICANT Jussi TENHUNEN et al.	
37 CFR 1.98(b)		FILING DATE March 27, 2002	GROUP Unassigned

**U.S. PATENT DOCUMENTS**

EXAMINER INITIAL	PATENT NUMBER	ISSUE DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
AA	5,631,735	05/97	Nagai			
AB	4,790,654	12/88	Clarke			
AC	4,790,652	12/88	Unéus et al.			
AD	5,856,871	01/99	Cabib et al.			
AE	4,448,529	05/84	Krause			
AF						

FOREIGN PATENT OR PUBLISHED FOREIGN PATENT APPLICATION

	DOCUMENT NO.	PUBL. DATE	COUNTRY OR PATENT OFFICE	CLASS	SUB CLASS	TRANSLATION YES NO
AI	0 550 076 A1	07/93	EP			
AJ	0 548 830 A1	06/93	EP			
AK	85/04261	09/85	WO			
AL						
AM						
AN						
AO						
AP						
AQ						

OTHER DOCUMENTS (Including Author, Title, Date, Relevant Pages, Place of Publication)

AT	
AU	
AV	
AX	
AY	

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